

Search Notes

Application/Control No.

10/823,170

Examiner

Yonel Beaulieu

Applicant(s)/Patent under
Reexamination

NAIK ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	1	1/18/2007	YB
	29		
	34		
	36		
702	108		
	127		
714	735		
	736		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST	1/19/2007	YB